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 State-of-the-Art Advanced BiCMOS	SN54LVT16500 WD PACKAGE
Technology (ABT) Design for 3.3-V	SN74LVT16500 DGG OR DL PACKAGE
Operation and Low-Static Power	(TOP VIEW)
Dissipation	
 Members of the Texas Instruments Widebus™ Family 	OEAB 1 56 GND LEAB 2 55 CLKAB A1 3 54 B1
 Support Mixed-Mode Signal Operation (5-V	GND [4 53] GND
Input and Output Voltages With 3.3-V V _{CC})	A2 [5 52] B2
 Support Unregulated Battery Operation	A3 6 51 B3
Down to 2.7 V	V _{CC} 7 50 V _{CC}
 UBT[™] (Universal Bus Transceiver)	A4 [8 49] B4
Combines D-Type Latches and D-Type	A5 [9 48] B5
Flip-Flops for Operation in Transparent,	A6 0 10 47 86
Latched, or Clocked Mode	GND 11 46 GND
• Typical V _{OLP} (Output Ground Bounce)	A7 [12 45] B7
< 0.8 V at V _{CC} = 3.3 V, $T_A = 25^{\circ}C$	A8 [13 44] B8
 ESD Protection Exceeds 2000 V Per	A9 [] 14 43 [] B9
MIL-STD-883, Method 3015; Exceeds 200 V	A10 [] 15 42 [] B10
Using Machine Model	A11 [] 16 41 [] B11
(C = 200 pF, R = 0)	A12 [] 17 40 [] B12
	GND 🛛 18 39 🗍 GND
 Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17 	A13 🛛 19 🛛 38 🛛 B13
	A14 20 37 B14
Bus Hold on Data Inputs Eliminates the	A15 21 36 B15
Need for External Pullup/Pulldown	V _{CC} [] 22 35 [] V _{CC}
Resistors	A16 [] 23 34 [] B16
Support Live Insertion	A16 [23 34] B16 A17 [24 33] B17
••	GND 25 32 GND
 Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise 	A18 26 31 B18
 Flow-Through Architecture Optimizes	ОЕВА 27 30 ССКВА
PCB Layout	СЕВА 28 29 GND

 Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The 'LVT16500 are 18-bit universal bus transceivers designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment.

Data flow in each direction is controlled by output-enable (OEAB and OEBA), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if CLKAB is held at a high or low logic level. If LEAB is low, the A-bus data is stored in the latch/flip-flop on the high-to-low transition of CLKAB. Output-enable OEAB is active high. When OEAB is high, the B-port outputs are active. When OEAB is low, the B-port outputs are in the high-impedance state.



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SN54LVT16500, SN74LVT16500 3.3-V ABT 18-BIT UNIVERSAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS SCBS146D – MAY 1992 – REVISED NOVEMBER 1996

description (continued)

Data flow for B to A is similar to that of A to B but uses OEBA, LEBA, and CLKBA. The output enables are complementary (OEAB is active high and OEBA is active low).

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver. OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

The SN74LVT16500 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed circuit board area.

The SN54LVT16500 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74LVT16500 is characterized for operation from -40° C to 85° C.

	INPUTS										
OEAB	LEAB	Α	В								
L	Х	Х	Х	Z							
н	Н	Х	L	L							
н	Н	Х	Н	Н							
н	L	\downarrow	L	L							
н	L	\downarrow	Н	н							
н	L	Н	Х	в ₀ ‡ в ₀ §							
н	L	L	Х	в ₀ §							

FUNCTION TABLET

[†] A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, and CLKBA.

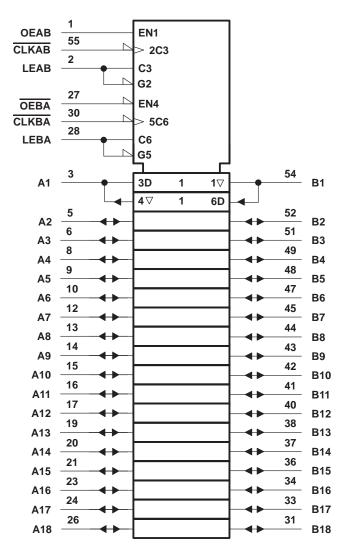
[‡]Output level before the indicated steady-state input conditions were established

§ Output level before the indicated steady-state input conditions were established, provided that CLKAB was low before LEAB went low



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logic symbol[†]

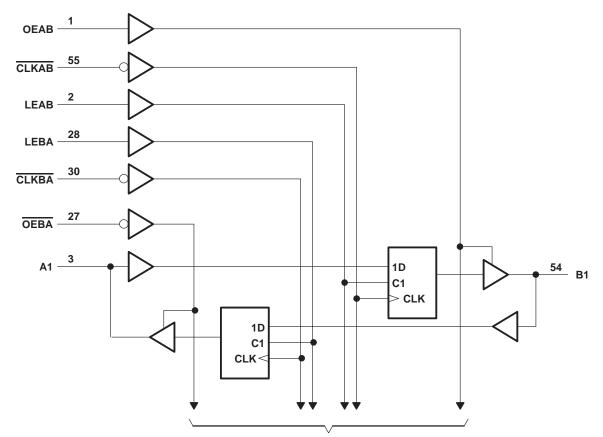


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



To 17 Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O (see Note 1)	
Current into any output in the low state, I _O : SN54LVT16500	96 mA
SN74LVT16500	128 mA
Current into any output in the high state, I _O (see Note 2): SN54LVT16500	48 mA
SN74LVT16500	64 mA
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 3): DGG package	
DL package	1.4 W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. This current flows only when the output is in the high state and $V_O > V_{CC}$.

3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



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recommended operating conditions (see Note 4)

			SN54LV	T16500	SN74LV	UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	2.7	3.6	2.7	3.6	V	
VIH High-level input voltage				ĬEI,	2		V
VIL	Low-level input voltage					0.8	V
VI						5.5	V
ЮН	High-level output current		S.	-24		-32	mA
IOL	Low-level output current		00	48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	40	10		10	ns/V
Т _А	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			SNS	54LVT16	500	SN7	UNIT		
							MIN	TYP [†]	MAX	UNIT
VIK	V _{CC} = 2.7 V,	lj = -18 mA			-1.2			-1.2	V	
	V_{CC} = 2.7 V to 3.6 V,	I _{OH} = -100 μA	V _{CC} -0	.2		V _{CC} -0	.2			
Vari	V _{CC} = 2.7 V,	I _{OH} = -8 mA		2.4			2.4			v
VOH	V _{CC} = 3 V	I _{OH} = -24 mA	2						v	
	VCC = 3 V	I _{OH} = -32 mA					2			
	V _{CC} = 2.7 V	I _{OL} = 100 μA				0.2			0.2	
	VCC - 2.7 V	I _{OL} = 24 mA				0.5			0.5	
VOL		I _{OL} = 16 mA				0.4			0.4	v
VOL	V _{CC} = 3 V	I _{OL} = 32 mA				0.5			0.5	v
		I _{OL} = 48 mA			0.55					
		I _{OL} = 64 mA		NE				0.55		
	V _{CC} = 3.6 V,	$V_I = V_{CC}$ or GND	Control inputs		Pr-	±1			±1	1
	$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V			Z	10			10	
lj –	V _{CC} = 3.6 V	V _I = 5.5 V			52	20			20	μΑ
		$V_I = V_{CC}$	A or B ports‡	Ó	~	5			5	
		$V_{I} = 0$		Q		-10			-10	
l _{off}	$V_{CC} = 0,$	$V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5$	V			±100			±100	μΑ
1.a	V _{CC} = 3 V	V _I = 0.8 V	A or B ports	75			75			μA
l(hold)	VCC = 3 V	V _I = 2 V	A of B ports	-75			-75			μΛ
IOZH	V _{CC} = 3.6 V,	$V_{O} = 3 V$				1			1	μΑ
IOZL	V _{CC} = 3.6 V,	$V_{O} = 0.5 V$	-			-1			-1	μΑ
			Outputs high			0.12			0.12	
Icc	V _{CC} = 3.6 V,	I _O = 0,	Outputs low			5			5	mA
	$V_I = V_{CC}$ or GND		Outputs disabled			0.12	0.12			
∆ICC§	$V_{CC} = 3 V \text{ to } 3.6 V$, One input at $V_{CC} - 0.6 V$, Other inputs at V_{CC} or GND					0.2			0.2	mA
Ci	V _I = 3 V or 0				3.5			3.5		pF
C _{io}	V _O = 3 V or 0				12			12		pF

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. [‡] Unused pins at V_{CC} or GND

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			SN54LVT16500				SN74LVT16500				
			V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	150	0	125	0	150	0	125	MHz
t _w Pulse duration	LE high	3.3		3.3		3.3		3.3		ns	
	CLK high or low	3.3		3.3		3.3		3.3		115	
	A before $\overline{\text{CLKAB}}\downarrow$	1.8		1.1		1.8		1.1			
	t _{su} Setup time	B before $\overline{CLKBA}\downarrow$	1.9	1	1.2		1.9		1.2		
tsu		A or B before LE \downarrow , CLK high	2.2	5	1.3		2.2		1.3		ns
	A or B before LE \downarrow , CLK low	2.7	0	1.9		2.7		1.9			
t _h Hold time	A or B after $\overline{CLK}\downarrow$	1.2	Q	1.2		1.2		1.2		~~~	
	A or B after LE \downarrow	0.9		1.1		0.9		1.1		ns	

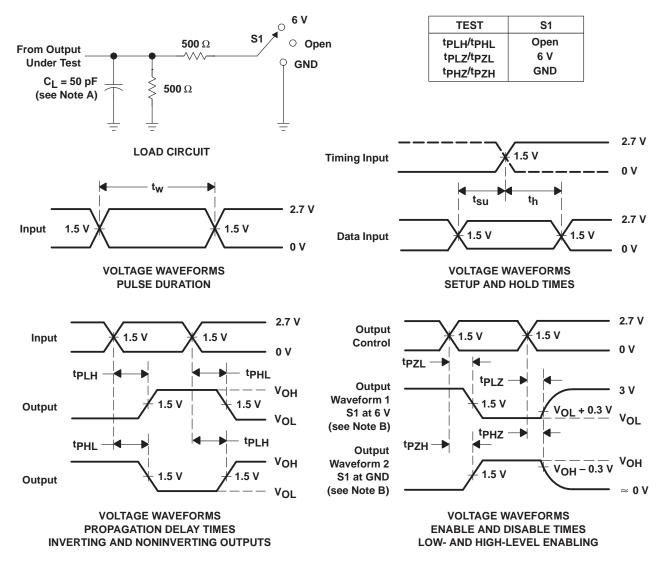
switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

				SN54LVT16500				SN74LVT16500						
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = ± 0.		V _{CC} =	2.7 V		C = 3.3 ± 0.3 V	V	V _{CC} =	2.7 V	UNIT		
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN	MAX			
fmax			150		125		150			125		MHz		
^t PLH	D or A	A or B	1.7	5.8		7	1.7	3	5.4		6.8	ns		
^t PHL	B or A	AUB	1.6	6	MJ,	7.8	1.6	3.2	5.9		7.7	115		
^t PLH				A or B	2.3	7.3	EL	8.9	2.3	4	7		8.5	ns
^t PHL	LEBA or LEAB	AUB	2.7	8.2	40	9.8	2.7	4.3	7.9		9.7	115		
^t PLH	CLKBA or	A or B	2	7.4	h	8.8	2	4.1	7		8.3	ns		
^t PHL	CLKAB	AUB	2.4	8.1		10	2.4	4.4	7.9		9.9	115		
^t PZH	OEBA or	A or B	1.2	5.2		6.1	1.2	3	5		5.9	ns		
^t PZL	OEAB	AUB	1.5	5.9		7	1.5	3	5.8		6.9	115		
^t PHZ	OEBA or	A or B	2.7	7.7		8.6	2.7	4.6	7.4		8.3	ns		
^t PLZ	OEAB	AUB	2.8	7.3		7.7	2.8	4.7	6.7		7.2	115		

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C.



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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